

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/687,288	YUEH ET AL.	
Examiner	Art Unit	
DABORAH CHACKO DAVIS	1795	

	SEARCHED		
Class	Subclass	Date	Examiner

INT	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
interferen	Interference search- interference search history print out		DCD		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
(430/270.1,322,9,311)-updated text search only-see updated search history print out	9/1/2010	DCD		
EAST(USPAT, US-PGPUB, FPRS, EPO, JPO, IBM-TDB, DERWENT)-see updated search history print out	9/1/2010	DCD		
Updated search histopry print out	9/1/2010	DCD		
eDAN inventor search performed	9/1/2010	DCD		